

SIR 13 mini New Release!



Insulation Degradation Evaluation System

- A reliability evaluation which requires many specimens and characteristics evaluation (an ammeter/voltmeter per specimen) can be simultaneously performed.
- The continuous automatic measurement within the chamber allows accurate detection of the beginning and ending of ion migration.
- The system is designed for 3-way use, namely ion migration detection, insulation resistance measurement, and insulation characteristics evaluation.

By selecting the necessary measurement boards, the system will perform ion migration detection, insulation resistance measurement, and insulation characteristics evaluation at the same time.

The 3-way use evaluation system: ion migration detection, insulation resistance measurement, and insulation characteristics evaluation

In 1994, ETAC released the industry's first automatic measurement system, "SIR 10" which electrically captures the phenomena of ion migration. Since then, we have been continually improving the system and in 2005, it has evolved into the "SIR 13" and "SIR 13 mini". With the improvement, these systems can now be used for various applications including insulation characteristics evaluation at material development phase, in addition to the measurement of insulation deterioration which is typified by migration phenomenon.



SIR 13 mini + HAST chamber "PLAMOUNT (PM420)" SIR 13 mini + Temperature/humidity chamber "Keyless HIFLEX (TH 402A)"

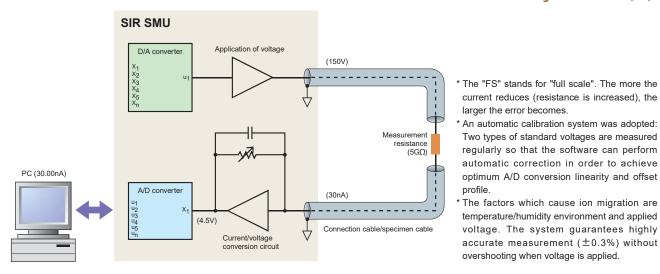


Temperature/humidity chamber "Keyless HIFLEX (TH 403A)"

Main features

- 1) New measurement board (120V) which is equipped with a power supply and an ammeter (an ammeter per specimen) per measurement circuit was developed (applied voltage: 120V, with specimen disconnection alarm function based on 8 channels, a four-wire Kelvin bridge method). Test conditions can be changed per channel and multiple tests with different conditions (up to 48 conditions) can be performed at the same time.
- 2) Multiple measurement boards with different applied voltage (120V, 250V, 500V, 1KV) can be simultaneously measured.
- 3) With the improved PC screens switching speed and the development of multi-tasking screen software, the data recording can be speedily performed during the test or after the test.
- 4) The system is designed for 3-way use, namely ion migration detection, insulation resistance measurement, and insulation characteristics evaluation.

• Micro current measurement method which achieves the measurement accuracy of $\pm 0.3\%$ (FS)

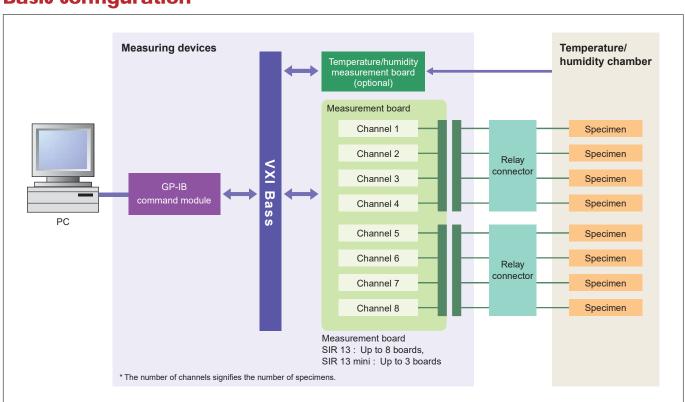


• A constant measurement interval of 40msec was achieved regardless of the number of specimens

In order to eliminate a humming sound, measurements are carried out 8 times within the 2 power source cycle time (50/60Hz) and the measurement data are obtained by averaging these values. (1/50Hz = 20msec, 20msec × 2 power source cycle time = 40msec)

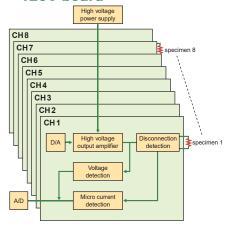
Because high-speed voltage/current measurement (A/D conversion) of 8 channels are carried out 8 times each within 40msec, the measurement interval of 40msec is maintained regardless of the number of specimens (8 channels to 128 channels).

Basic configuration



Types of measurement board and measurement circuit

•120V board

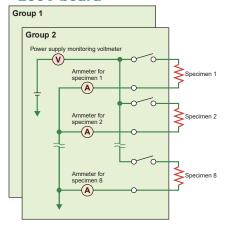


- Maximum 8 channels. A DC voltage generator and a DC ammeter come with every channel. Different test conditions can be set for each channel. Suitable for materials evaluation which requires performing multiple tests with different settings.
- •DC four-wire Kelvin bridge method to detect specimen connection error. (Measurement can also be made through two-wire connection.)
- •Voltage range: 120.00V/12.00V

(set to the best range automatically)

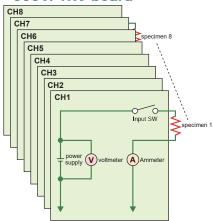
•Current range: 320.00 μA/3.2000 μA/ 32.000nA/auto range

•250V board



- •Maximum 16 channels, 8 channels per group. A DC voltage generator comes with every group and a DC ammeter comes with every channel. Useful for an evaluation of components which need to be tested in large quantity or a certification evaluation, etc.
- •Voltage range: 250.00V
- •Current range: 320.00μA/3.2000μA/auto range
- * Because multiple channels in a group share the same power supply, if a current limiter is activated on a certain channel, applied voltage on other channels may be reduced temporarily. However, by specifying the voltage error channel (defective specimen) using the current check function, tests of other channels will be continued without interruption.

•500V/1KV board



- Maximum 8 channels. Eight channels per group.
 A DC voltage generator and a DC ammeter come with every channel. Best suited for the test of components which require high voltage applications such as automotive electronics components.
- •Voltage range: 500.0V or 1000.0V
- •Current range: 320.00μA/3.2000μA/

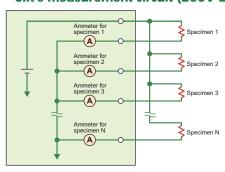
32.000nA/auto range

Comparison with the scanner measurement (relay) method

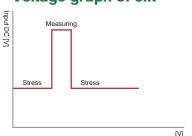
Because the SIR adopted the continuous measurement method which captures every ion migration phenomenon without fail, as compared with the scanner measurement (relay) circuit, the system offers the following advantages.

- 1) Because a power supply and an ammeter is equipped per every channel, there is no need for switching relays and thus, no measurement data will be omitted. (120V, 500V, and 1KV boards only)
- 2) Because of its high-speed measurement sequence, there will be no changes in measurement intervals (40msec) even if the number of specimens is increased. (**See P.2.)
- 3) When the scanner measurement (relay) method is used, the voltage application may be interrupted (0V) when the relays are switched.

• SIR's measurement circuit (250V board)

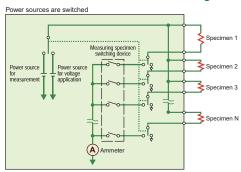


Voltage graph of SIR

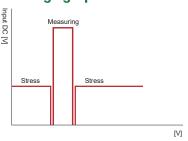


* Continuously measured because there is no need to

Scanner measurement (relay) circuit



• Voltage graph of scanner measurement (relay) circuit



The voltage drops to 0V while the scanner boards

SIR main body and board configuration





•SIR 13: 8-slot

•SIR 13 mini: 8-slot

•List of measurement boards with excellent cost performance

Measurement board	Applied voltage	Power supply and ammeter	No. of channels	Setting of test conditions
120V board	0.10~120.00V 0.100~12.000V	1 power supply, 1 ammeter/channel	8 channels	Per channel
250V board Measurement current range: 2-range and 3-range specifications are available	asurement current range: 0.1~250.0V		16 channels	Per 8 channels
500V board	1.0~500.0V	1 power supply,	8 channels	Per 8 channels
1KV board	1.0~1000.0V	1 ammeter/channel		

^{*} For more detailed specifications, please refer to the Specifications Table in Page 8.

Temperature/humidity continuous measurement within the chamber provides highly reliable data.

... Our effective external noise prevention technique for high resistance, micro current measurement

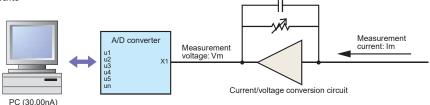
1) Shielded measurement cables



Dedicated specimen cable for the SIR

The measurement cables can be easily affected by external noise due to high impedance and micro measurement current. In order to solve this problem, ETAC provides shielded dedicated cables (measurement cables).

2) Filtering of current-voltage conversion circuits



The system comes with the active low-pass filter that reduces noise of 70Hz to -20dB (1/10) and 700Hz to -40dB (1/100).

3) Filtering with software

The measurement current converted into voltage is digitally converted with the A/D converter, and the data is accumulated and averaged at every power source cycle time (50/60Hz) with the software installed in the measurement board in order to remove the low frequency noise (humming sound) which is generated at every power source cycle.

Measurement mode

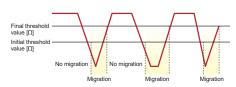
Migration measurement mode

Beginning of migration	When the measurement resistance value exceeds the migration initial threshold value, the system will recognize it as the beginning of migration.
Migration in progress	During the migration process, data of up to 151 points per SMU board are collected every 40msec. However, if there are more than 151 points from which data is collected, the recording interval will be doubled and the data to be collected is thinned out.
Ending of migration	When the measurement resistance value exceeds the migration final threshold value, the system will recognize it as the ending of migration.

* The "SMU" stands for source measurement unit.

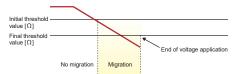
Time-triggered data collection mode

From the beginning to the end of the test time, voltage is continuously applied even if migration is detected and measurement data is also continuously collected.



Point-triggered data collection mode

When ion migration occurred, application of voltage is stopped only for the specific channel and the data is collected.



Group-triggered data collection mode

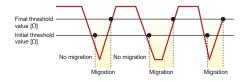
When ion migration occurs, the application of voltage is stopped for the entire group which includes the channel (a "group" is defined as up to 8 specimens connected by the same connector) and the data collection is terminated.

Leak check measurement mode

The SIR judges the migration beginning point at high speed (400μ sec/1ch)and the data at the point of time when the migration occurred is recorded in the PC.

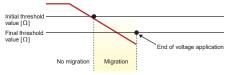
Time-triggered data collection mode

From the beginning to the end of the test time, voltage is continuously applied even if a migration is detected and the data at the measurement points (•) as indicated in the graph below are collected.



Point-triggered data collection mode

When an ion migration occurs, the application of voltage is stopped only for the specific channel and the data at the measurement points (•) as indicated in the graph below are collected.

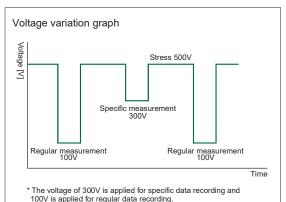


Group-triggered data collection mode

When ion migration occurs, the application of voltage is stopped for the entire group which includes the channel (a "group" is defined as up to 8 specimens connected by the same connector) and the data collection is terminated.

Insulation resistance measurement mode

The stress voltage and the measurement voltage are set separately and the latter is changed at every set time and measurement is made accordingly. While stress voltage is applied, ion migration measurements can be performed at any time. (The system allows ion migration and insulation characteristics evaluations simultaneously.)



- 1) The measurement voltage is applied at preset data recording intervals for measurement. The measurement values are recorded on the PC. Apart from this, stress voltage is applied.
- Judgment: Regardless of whether either stress voltage or measurement voltage is applied, error judgment (absolute value judgment) is made for the measurement.
- 3) While stress voltage is applied, ion migration measurement is performed. The migration measurement is regarded the same as the time-triggered data collection mode of the migration measurement mode and migration evaluation can be made while the stress voltage is applied.
- 4) The minimum measurement and data collection interval is 30 seconds
- 5) Measurement sequence at insulation resistance measurement mode
 - Usually, the stress voltage is applied to monitor the current value.
 - The measurement values while the stress voltage is applied are not transmitted to the PC unless judged as an error.
 - If the monitored value exceeds the threshold value or voltage is found abnormal, measurement of the channel is ended.
 - The preset voltage is applied during the regular data recording period for measurement.
 - The preset specific data recording voltage is applied during the specific data recording period (2 points~10 points setting) for measurement.

Functions of temperature/humidity measurement board (optional)

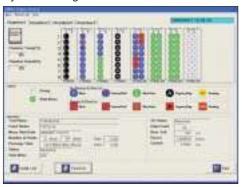
By using an optional temperature/humidity measurement board, temperature/humidity within chamber is measured and recorded after the set temperature/humidity is reached. The sensor is compatible with the T type thermocouple and resistance temperature sensor (Pt100). Up to 3 different temperature/humidity test can be performed simultaneously.

Application software

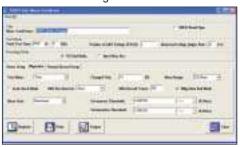
- With the dedicated software, a PC can control the entire system (the SIR and temperature/humidity test chamber = Keyless Chamber) simultaneously.
- With the improved screens switching speed and the development of multi-tasking screen software, the data analysis can be speedily performed during the test or after the test.

System management

System management screen



Test condition setting screen



- * The data used to create a graph can be plotted on a log scale.
- * The collected data is output in ASCII format.
- * The data processing software is sold separately. Please contact us for more details.
- * The software operates with Windows 2000 and above.

Data management

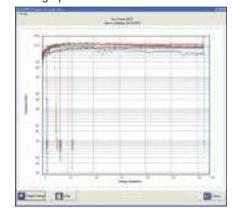
List of past data



Migration data



Data graph



Weibull graph (Optional)



Evaluation examples

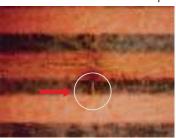
• Example of printed circuit board ion migration

Surface of a substrate

ion migration occurred.



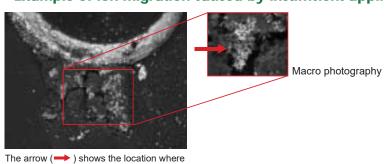
Observation with a dark-field microscope

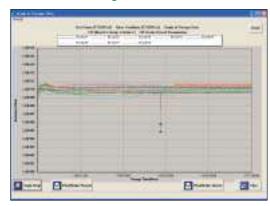


The arrow () shows the location where ion migration occurred.



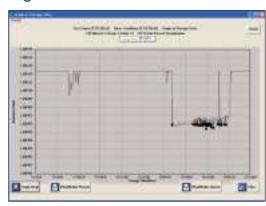
• Example of ion migration caused by insufficient application of secondary sealant





• Example of ion migration caused by a pinhole in the coating film





The arrow () shows the location where ion migration occurred.

* For inquiries on evaluation results or request for a failure analysis, please contact ETAC's "Reliability Clinic" (See Page 10).

SIR Specifications Table

	Pro	duct name		Insulation degradati	on evaluation system				
	Λ.	Andal Na		SIR 13					
Model No.			120V board	250V board		500V board	1kV board		
Measurement board Resistance measurement range No. of measurement channels Connection cable		320Ω~120ΤΩ	320Ω~2.5TΩ	320Ω~250TΩ	320Ω∼500ΤΩ	320Ω∼1000ΤΩ			
		8 channels/board	16 chann	16 channels/board		8 channels/board			
				2 cables/board (connection cab		2 cables/board (connection cable),		2 cables/board (connection cable),	
		Connection cable		four-wire Kelvin Bridge meth	input voltage measurement cable ×2		voltage application cable×1, measurement cable>		
		Applied voltage	Range 1		0.1~250.0V		1.0~500.0V	1.0~1000.0V	
		Applied voltage	Range 2	0.100~12.000V	_				
	Application	Resolution		0.01V/0.001V	0.1		1V		
		Basic accuracy			±0.3%/FS		±0.3%+0.5V/FS		
		Maximum output power		96mW/channel	256mW/8	Bchannels	300mW/channel		
	of voltage		No. of groups to apply voltage		_	2 groups (8 channels/group)		1 group (8 channels/group)	
		_ ,		1 group (1 channel/grou	p) 2 groups (0				
		No. of voltage applied ranges		2 ranges	1 range				
		No. of channels to		1 channel			annels		
		Maximum load ca	rrying capacity	2.0µF/1channel	0.47µF/8	Schannels	3300pF/	1channels	
		No. of monitoring	ranges	2 ranges		1 ra	ange		
		Monitoring range	Range 1	0.00~120.00V	0.0~	250.0V	0.0~500.0V	0.0~1000.0V	
		Worldoning range	Range 2	0.000~12.000V	_				
	Voltage	Monitoring resolut	ion	0.01V/0.001V		0.			
Elec	monitor	Basic monitoring a	accuracy		±0.3%/FS		±0.3%	+0.5V/FS	
ctric		Monitoring unit		1 channel	1 q	roup	1 ch	annel	
cha		Monitoring cycle				40msec/8channels			
arac		No. of monitoring	channels	8 channels	16 ch	annels	8 ch	annels	
teri		•						aririois	
Electric characteristics		No. of measureme		3 ranges	2 ranges				
		Measurement	Range 1			<u></u>	0μA~320.00μA		
		range	Range 2			0.0000μA~3.2000μA	μΑ		
			Range 3	0.000nA~32.000n	A		0.000nA~32.000nA		
		Range setting		320.00μA, 3.2000μA, 3.200μA, 3.2000μA, 3.2000μA, 3.2000μA, 3.2000μA, 3.2000μA, 3.2000				auto range	
		Dange 1		10nA	10nA 10nA				
	Measurement	Minimum resolution	Range 1						
	of electric		Range 2	100pA	100pA		100pA		
	current		Range 3	1pA 1pA					
		Basic measurement accuracy		±0.3%/FS					
		No. of channels		8 channels 8 channels					
		Recording cycle		Every 30 seconds (minimum)/when ion migration occurs, every 40 msec (minimum)					
		Migration measurement speed		40 msec/8 channels					
		Leakage current detection		400µsec/channel					
		Measuring cycle		8 channels/40 msec					
		Self diagnosis		An external resistor is connected for diagnosis (optional)					
		Interlock		Automatic measurement interrupt function while the chamber door is open (optional).					
		Data dia a af dia a		Terminal disconnection					
0.11		Detection of disco	nnection	detection function					
Otne	er functions	Temperature/hum	idity recording	By adding temperature/humidity measurement boards and by using 3CS • Keyless software, data can be collected from up to 4 chambers (opt					
		Specimen's temper	ature recording	By combin	ng with 3CS software, eac	with 3CS software, each SMU channel records		temperature of a chamber (optional).	
		Maximum	SIR 13	64 channels (8 boards	128 channe	els (8 boards)	64 channe	ls (8 boards)	
		No.of channels	SIR 13 mini	24 channels (3 boards	48 channel	s (3 boards)	24 channe	ls (3 boards)	
					Windows XP Pro. SP2 (also compatible with Windows 2000), Pentium III, 500MHz or above, memory: 256Mbyte and above				
		System control P0	<u> </u>	Windows XP Pro. SP2	also compatible with Windows 2	000), Pentium III, 500MHZ of	above, memory. Zoowbyte a	iiu above	
Cont	trol unit				also compatible with Windows 2	000), Pentium III, 500MHZ or	above, memory. 230mbyte a	ma above	
		System control PC	easurement unit	GP-IB or Ethernet	·				
		System control PC	easurement unit	GP-IB or Ethernet The data collected just	pefore power failure is saved to o				
		System control PC	easurement unit	GP-IB or Ethernet The data collected just SIR 13 S	·	enable continued measureme	nt. *A UPS is necessary	(to be purchased separa	
Cont		System control PC	easurement unit	GP-IB or Ethernet The data collected just I SIR 13 S E: W	pefore power failure is saved to of MU 8-slot type sternal dimensions : W43 eight : abou	enable continued measuremen 0×H300×D620mm *D tt 30 Kg (when 8 SMU b	ont include projecting pards are loaded)	(to be purchased separa	
		System control PC	easurement unit	GP-IB or Ethernet The data collected just I SIR 13 S E W C	before power failure is saved to or MU 8-slot type tternal dimensions : W43 eight : abou consumption current : Less	enable continued measuremen 0×H300×D620mm *D tt 30 Kg (when 8 SMU b	ont include projecting pards are loaded)	(to be purchased separa	
		System control PC Connection with the m Countermeasures again	easurement unit	GP-IB or Ethernet The data collected just I SIR 13 S E: W C SIR 13 mini S	pefore power failure is saved to of MU 8-slot type sternal dimensions : W43 eight : abou	enable continued measurement 0×H300×D620mm *D t 30 Kg (when 8 SMU b than 5A (when using 10	onot include projecting oards are loaded)	(to be purchased separa	
Othe	ers	System control PC Connection with the m Countermeasures again	easurement unit	GP-IB or Ethernet The data collected just I SIR 13 S E: W C SIR 13 mini S E: W	before power failure is saved to or MU 8-slot type teernal dimensions : W43 eight : about onsumption current : Less MU 3-slot type teernal dimensions : W22 eight : about abou	enable continued measurement 0 × H300 × D620mm *D tt 30 Kg (when 8 SMU b than 5A (when using 10 0 × H370 × D390mm *D tt 20 Kg (when 3 SMU b	ont. *A UPS is necessary o not include projecting pards are loaded) 00V) o not include projecting pard are loaded)	(to be purchased separal	
Othe		System control PC Connection with the m Countermeasures again	easurement unit	GP-IB or Ethernet The data collected just I SIR 13 S E: W C SIR 13 mini S E: W	before power failure is saved to on the failure is saved to one of the failure is saved to on	enable continued measurement 0 × H300 × D620mm *D tt 30 Kg (when 8 SMU b than 5A (when using 10 0 × H370 × D390mm *D tt 20 Kg (when 3 SMU b	ont. *A UPS is necessary o not include projecting pards are loaded) 00V) o not include projecting pard are loaded)	(to be purchased separat	
Othe	ers	System control PC Connection with the m Countermeasures again	easurement unit	GP-IB or Ethernet The data collected just I SIR 13 S E: W C SIR 13 mini S E: W	before power failure is saved to on the saved to on the saved to on the saved to one saved to on	enable continued measurement 0 × H300 × D620mm *D tt 30 Kg (when 8 SMU b than 5A (when using 10 0 × H370 × D390mm *D tt 20 Kg (when 3 SMU b	ont. *A UPS is necessary o not include projecting pards are loaded) 00V) o not include projecting pard are loaded)	(to be purchased separal	
Othe	ers	System control PC Connection with the m Countermeasures agai Available sizes	easurement unit nst power failure	GP-IB or Ethernet The data collected just I SIR 13 SE W C SIR 13 mini SE W C C	before power failure is saved to out the failure is saved to save the failure is saved to saved the failure is saved the failure is saved the failure is saved to saved the failure is saved the failure is saved to saved the failure	enable continued measurement 0 × H300 × D620mm *D tt 30 Kg (when 8 SMU b than 5A (when using 10 0 × H370 × D390mm *D tt 20 Kg (when 3 SMU b	ont. *A UPS is necessary o not include projecting pards are loaded) 00V) o not include projecting pard are loaded)	(to be purchased separat	
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Othe	ers	System control PC Connection with the me Countermeasures agai Available sizes Noise resistance Insulation resistar	easurement unit inst power failure	GP-IB or Ethernet The data collected just i SIR 13 S E: W C SIR 13 mini S: W C 1 μ sec pulse 2KV DC500V 100M Ω at AC85V \sim 264V 50/	before power failure is saved to or MU 8-slot type ternal dimensions : W43 eight : about showing the consumption current : Less MU 3-slot type ternal dimensions : W22 eight : about showing the current : Less I minute above	enable continued measurement 0 ×H300 ×D620mm *D it 30 Kg (when 8 SMU b than 5A (when using 10 0 ×H370 ×D390mm *D it 20 Kg (when 3 SMU b than 2A (when using 10	ont. *A UPS is necessary o not include projecting pards are loaded) 100V) o not include projecting pard are loaded) 100V)	(to be purchased separat parts. parts.	

^{* 3}CS: The brand name of ETAC's "Environmental test chamber central control and monitoring software".

Recommended temperature/humidity test chamber

HIFLEX Keyless series

Network compatible temperature (humidity) chamber

Network compatible Keyless Chamber

This is the industry's first keyless environmental test chamber (settings, operation, and monitoring are performed with a PC) with high performance equivalent to ETAC's standard temperature/humidity test chamber "HIFLEX" which realized space-savings, low price, and flexible system configurations. By using the TH 403A, the economy of space is tripled as up to 3 units can be stacked up to perform different tests individually. Moreover, because the SIR 13 mini can be stored inside a rack which comes with TH 401A and TH 402A, the effectiveness of space management is further enhanced and a complete automatic measurement system can be established within the space.

* Flexible system configuration:

The measurement cable can be easily connected because the measurement unit can be placed either on right or left side of the chamber according to your needs.



(TH 401A)

Quick reference for HIFLEX Keyless series model number and basic performance

Temperature/humidity chamber (internal dimensions: mm)	W500×H350×D350	(W500×H350×D350)×2	(W500×H350×D350)×3	W600×H600×D500	(W600×H600×D500)×2
−40°C∼+100°C(+150°C) 20%RH.∼98%RH.	TH 401A (H)	TH 402A (H)	TH 403A (H)	TH 411A (H)	TH 412A (H)
Temperature chamber (internal dimensions: mm)	W500×H350×D350	(W500×H350×D350)×2	(W500×H350×D350)×3	W600×H600×D500	(W600×H600×D500)×2
-40°C∼+100°C(+150°C)	TL 401A (H)	TL 402A (H)	TL 403A (H)	TL 411A (H)	TL 412A (H)

^{*} The "(H)" indicates that the model is a ± 150 °C maximum temperature specification model.

PLAMOUNT H series

Highly accelerated stress test chamber (HAST chamber)

The epoch-making, rectangular shape chamber accommodates various needs

We developed an epoch-making, rectangular shape HAST chamber for the first time in Japan in order to completely eliminate the problems caused by the traditional round shape chambers. In addition to unsaturated/saturated operation control functions, various new functions such as the specimen humidified storage function were added to enable more accurate and user-friendly operation. Moreover, because the SIR 13 mini can be stored in the middle space of the rack which comes with PM 220 and PM 420, it contributes further to space saving.



Quick reference for PLAMOUNT H series model number and basic performance

Temperature/humidity and pressure ranges internal dimensions: mm	W270×H300×D300	W370×H370×D380	W270×H300×D300×2	W370×H370×D380×2
Temperature range: +105°C∼+143°C Humidity range : 75%∼100%RH Pressure range : 0.2∼2.0kg/cm²G	PM220	PM250	PM222	PM252
Temperature range: +105°C∼+162°C Humidity range : 75%∼100%RH Pressure range : 0.2∼4.0kg/cm²G	PM420		PM422	